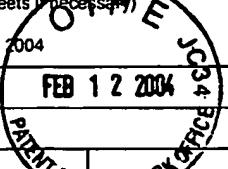


FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Submitted to the PTO: February 12, 2004			ATTY DOCKET NO. <b>02910.000098</b>		APPLICATION NO. <b>10/697,278</b>		
			APPLICANTS <b>SHIGEKI YABU, ET AL.</b>				
			FILING DATE <b>October 31, 2003</b>		GROUP <b>Unassigned</b>		
 U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	TRADEMARK DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JN		2002-0047513	04/2002	Nomura	313	495	
JN		6,400,091	06/2002	Deguchi, et al.	315	169.1	
JN		2002-0074947	06/2002	Tsukamoto	315	169.3	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
JN		2002-170483	06/2002	Japan	—	—	Abstract
JN		2000-268706	09/2000	Japan	—	—	Abstract
JN		2002-150925	05/2002	Japan	—	—	Abstract
JN		2000-251783	09/2000	Japan	—	—	Abstract
JN		2002-100279	04/2002	Japan	—	—	Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
JN		C.A. Spindt, et al., "Physical Properties of Thin-Film Field Emission Cathodes with Molybdenum Cones", Journal of Applied Physics, Vol. 47, No. 12, pp. 5248-5263 (December 1976).					
JN		M.I. Elinson, et al., "The Emission of Hot Electrons and the Field Emission of Electrons From Tin Oxide", Radio Engineering and Electronic Physics, No. 10, pp. 1290-1296 (July 1965).					
JN		C.A. Mead, "Operation of Tunnel-Emission Devices", Vol. 32, No. 4, pp. 646-652 (April 1961).					
EXAMINER		/Jennifer Nguyen/		DATE CONSIDERED		08/30/2006	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. <b>02910.000098</b>	APPLICATION NO. <b>10/697,278</b>		
				APPLICANTS <b>SHIGEKI YABU, ET AL.</b>			
				FILING DATE <b>October 31, 2003</b>	GROUP <b>2613</b>		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JN		6,437,503	08/2002	Konuma	313	495	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
JN		2000-243218	09/2000	Japan			
JN		2003-228316	08/2003	Japan			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER	/Jennifer Nguyen/			DATE CONSIDERED	08/30/2006		

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FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. <b>02910.000098</b>	APPLICATION NO. <b>10/697,278</b>		
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			APPLICANTS <b>SHIGEKI YABU, ET AL.</b>			
Submitted to the PTO: June 30, 2006			FILING DATE <b>October 31, 2003</b>	GROUP <b>2613</b>		
JUN 20 2006 RECEIVED EXAMINER INTERVIEW INFORMATION OFFICE U.S. PATENT AND TRADEMARK OFFICE U.S. PATENT DOCUMENTS						
EXAMINER	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JN	6,104,139	08/2000	Elloway, et al.	315	169.3	
JN	6,307,325	10/2001	Elloway, et al.	315	169.3	
JN	6,307,326	10/2001	Elloway, et al.	315	169.3	
JN	6,459,209	10/2002	Elloway, et al.	315	169.3	
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
JN	2002-524816	08/2002	Japan			Abstract
JN	WO 00/13167	03/2000	PCT			
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER	/Jennifer Nguyen/		DATE CONSIDERED	08/30/2006		

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